Schedule of Scope to Certificate of Conformity

Approved Process

IECQ Certificate No.: IECQ-P JQAJP 13.0009
CB Certificate No.: JQAQ 0014-001-M

Schedule Number: IECQ-P JQAJP 13.0009-S **Rev No.:4** **Revision Date:2018/12/28** **Page** 1 **of** 1

In respect of standards and specifications:

IEC 60747-1:2006
Semiconductor devices
- Part 1: General

IEC 60748-1:2002
Semiconductor devices - Integrated circuits
- Part 1: General

IEC 60748-20:1988
Semiconductor devices. Integrated circuits
- Part 20: Generic specification for film integrated circuits and hybrid film integrated circuits

ISO 9001:2015
Quality management systems - Requirements

Component:

Semiconductor devices, Integrated circuits, Hybrid integrated circuits.

Scope:

The design, manufacture and test of Semiconductor devices, Integrated circuits, Hybrid integrated circuits.

Japan Quality Assurance Organization (JQA)
4-4-4, Minamiosawa, Hachioji-shi, Tokyo 192-0364 Japan